

# **DAC080N120PY4**

# Silicon Carbide Enhancement Mode MOSFET

### **Features**

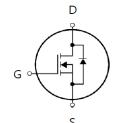
- High switching speed with a low gate charge
- Fast intrinsic diode with low reverse recovery
- Simple to drive with -5V/+18V gate
- · Increased power density
- Pb-free, Halogen Free, and RoHS Compliant

### **Benefits**

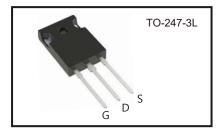
- Lower capacitance
- Higher system efficiency
- · Easy to parallel

# **Applications**

- Solar inverters
- · DC/DC converters
- · Switch mode power supplies
- · Induction heating
- · Motor drives



$V_{DSS}$	1200V
I <sub>D(@25°C)</sub>	30A
$R_{DS(ON)typ.}$	80mΩ



Package Dimensions

# A - A - E1 - A1

Unit	:	mm

Symbol	Min	Max		
Α	4.80	5.20		
A1	2.29	2.54		
A2	1.90	2.10		
b	1.10	1.30		
b1	1.91	2.20		
b2	2.92	3.20		
С	0.50	0.70		
D	20.80	21.34		
D1	17.43	17.83		
E	15.75	16.13		
E1	13.06	13.46		
E2	4.32	4.83		
е	5.45 BSC			
L	19.85	20.25		
L1	-	4.49		
ФР	3.55	3.65		
Q	5.59	6.19		
S	6.15 BSC			

# **Absolute Maximum Ratings**

(Tc = 25°C unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	1200	v
Gate - Source Voltage (DC)	V <sub>GS</sub>	-10/+22	v
Recommended Operation Value	V <sub>GS(op)</sub>	-5/+18	v
Drain Current-Continuous Tc=25°C Tc=100°C	I <sub>D</sub>	30 21	A
Pulse Drain Current	I <sub>DM</sub>	80	A
Total Power Dissipation	P <sub>D</sub>	P <sub>D</sub> 150	
Storage Temperature Range	T <sub>STG</sub>	-55 to +175	°C
Operating Junction Temperature Range	TJ	-55 to +175	°C



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# Electrical Characteristics @ T<sub>J</sub> =25°C (unless otherwise specified)

Parameter	Symbol	Conditions		Min.	Тур.	Max.	Unit
OFF Characteristics							
Drain-Source Breakdown Voltage	BVDSS	V <sub>G</sub> s=0V , I <sub>D</sub> =1mA		1200	-	-	V
Zero Gate Voltage Drain Current	Ipss	V <sub>DS</sub> =1200V V <sub>GS</sub> =0V	TJ=25℃	-	1	50	μA
			TJ=150°C	-	5	200	
Gate-Source Leakage Current	Igss	V <sub>GS</sub> = 22V , V <sub>DS</sub> = 0V	•	-	-	100	nA
Gate-Source Leakage Current	1655	V <sub>GS</sub> =-10V , V <sub>DS</sub> =0V		-	-	-100	
ON Characteristics	·						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =5mA		2.0	3.0	4.5	V
		.,	TJ=25°C	-	80	100	mΩ
Drain-Source On-State Resistance	RDS(on)	V <sub>GS</sub> = 18V , I <sub>D</sub> = 15A	TJ=175°C	-	128	-	
Internal Gate Resistance	R <sub>G</sub> (int.)	f=1MHz , V <sub>AC</sub> =25mV	1	-	4.0	-	Ω
Dynamic Characteristics							
Input Capacitance	Ciss		V <sub>DS</sub> =800V V <sub>GS</sub> =0V		890	-	
Output Capacitance	Coss	V <sub>DS</sub> =800V V <sub>GS</sub> =0V			65	-	pF
Reverse Transfer Capacitance	Crss	f =250kHz		-	6	-	
Turn-On Switching Energy	Eon	V <sub>DD</sub> =800V V <sub>GS</sub> =-5/+18V I <sub>D</sub> =15A R <sub>G(ext)</sub> =2.0Ω		-	186	-	μJ
Turn-Off Switching Energy	Eoff			-	46	-	
Total Switching Energy	Etot			-	232	-	
Switching Characteristics							
Turn-On Delay Time	t <sub>d(on)</sub>	\/ -000\/		-	16	-	_
Rise Time	tr	V <sub>DD</sub> =800V V <sub>GS</sub> =-5/+18V		-	23	-	
Turn-Off Delay Time	td(off)	$I_D = 15A$ $R_{G(ext)} = 2.0\Omega$		-	26	-	ns
Fall Time	tf			-	10	-	
Total Gate Charge	Qg	V <sub>DD</sub> =800V		-	53	-	
Gate to Source Charge	Qgs	V <sub>GS</sub> =-5/+18V			15	-	nC
Gate to Drain Charge	Qgd	I <sub>D</sub> =15A		-	18	-	
Body Diode Characteristics							
Diode Forward Voltage	Vsp	V <sub>GS</sub> =-5V , I <sub>SD</sub> =15A		-	4.1	-	V
Diode Source Current	Is			-	-	30	Α
Maximum Diode Source Current (DC)	Isм			-	-	80	Α
Reverse Recovery Time	Trr	I <sub>SD</sub> =15A , V <sub>DD</sub> =800V dir/dt=1000A/µs		-	34	-	ns
Reverse Recovery Charge	Qrr			-	112	-	nC
Thermal Resistance	·						
Thermal Resistance, Junction-to-Case	RθJc			-	-	1.0	°C/W

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# **Typical Performance**

Fig 1. Output Characteristics, T<sub>J</sub> = 25°C

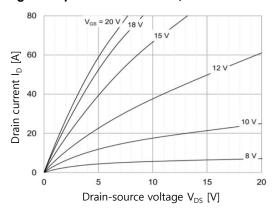


Fig 2. Output Characteristics, T<sub>J</sub> = 175°C

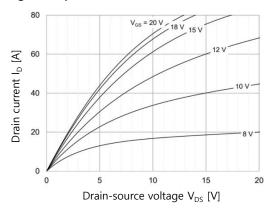


Fig 3. On-Resistance Variation vs. Temperature

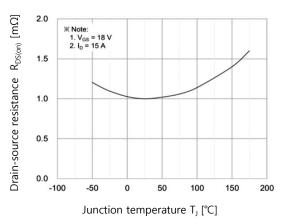


Fig 4. Transfer Characteristics

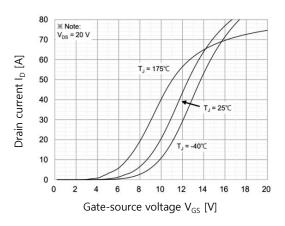


Fig 5. Threshold Voltage vs. Temperature

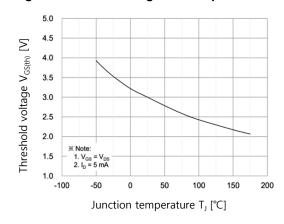
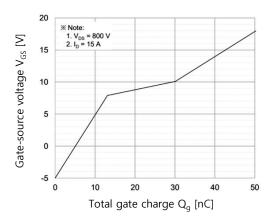


Fig 6. Gate Charge Characteristics



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### **Typical Performance**

Fig 7. Capacitance Characteristics

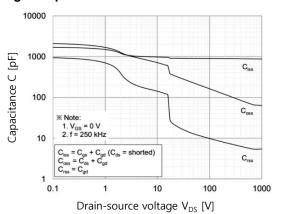


Fig 8. Stored Energy in Output Capacitance

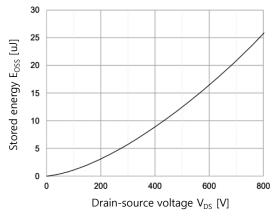


Fig 9. Body Diode Characteristics @ 25°C

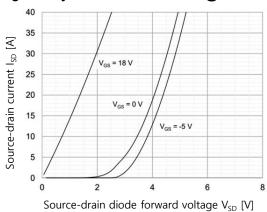


Fig 10. Body Diode Characteristics @ 175°C

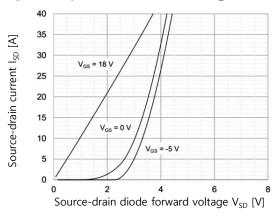


Fig 11. Max. PD Derating VS Case Temperature

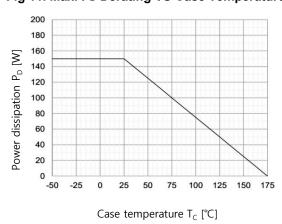
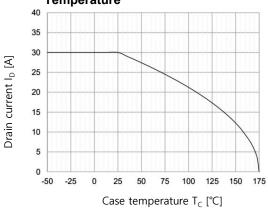


Fig 12. Continuous ID Derating VS Case Temperature



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# **Typical Performance**

Fig 13. Transient Thermal Impedance

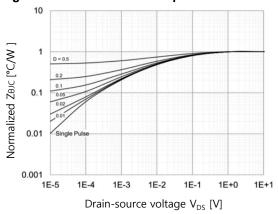


Fig 15. Clamped Inductive Switching Energy vs Drain Current

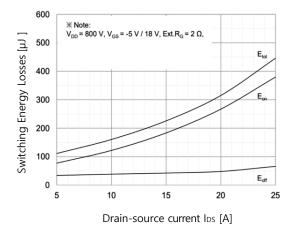


Fig 14. Safe Operating Area

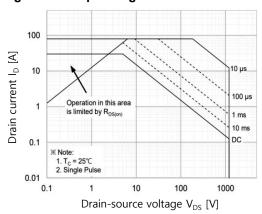
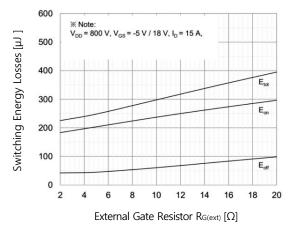


Fig 16. Clamped Inductive Switching Energy vs External Gate Resistor R<sub>G(ext)</sub>



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